

THE PERFECT BLEND OF INNOVATIVE DESIGN AND CUTTING EDGE TECHNOLOGY

XPLOR 100

3D OPTICAL INSPECTION STATION

The XPLOR 100 is a fully automated metrology device designed for measurement and analysis of bubbles and inclusions for optical substrates in the Visible and NIR wave-bands.

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XPLOR 100 SPECIFICATIONS

SPECIFICATION

XYZ Positioning Accuracy
Camera Resolution
Pixel Size
Measurement Area
Bit Depth
Frame Rate
Light Source
Wavelength Range

DESIGN VALUE

+/- 0.001mm
1280 X 1024
5.3um X 5.3um
100mm X 100mm X 100mm
10 Bits
60 fps
SiN3
400nm to 1000nm

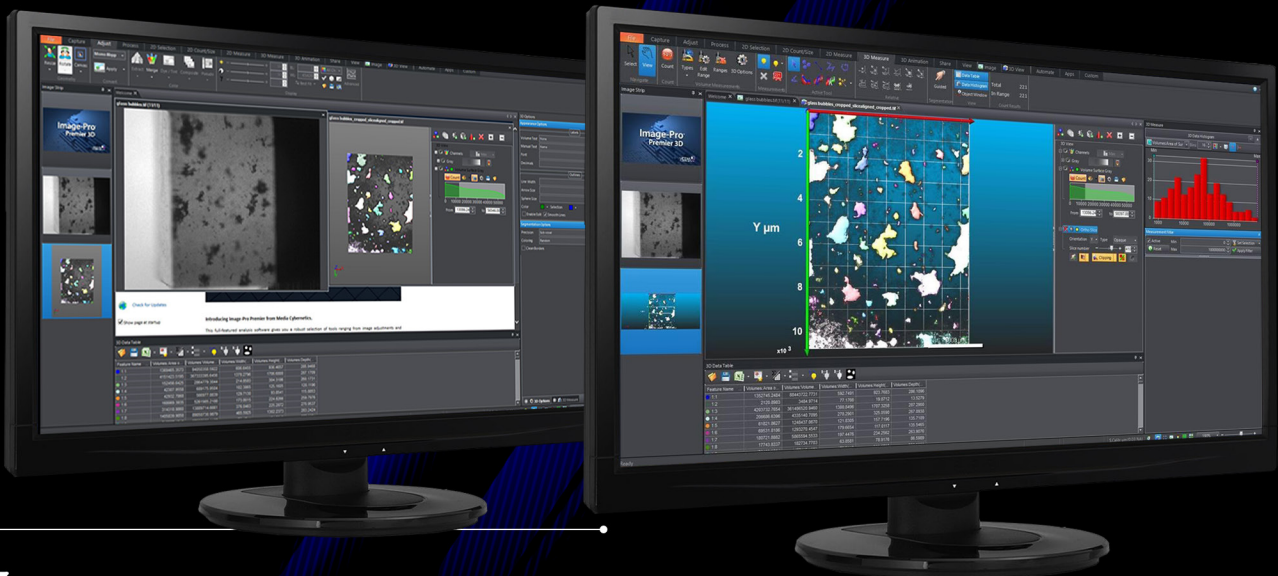
LENS OPTIONS

MAGNIFICATION	0.243X	0.528X	1.00X	2.00X
Working Distance	103 mm	44 mm	62.2 mm	55.9 mm
Depth of Field	±11 mm	±1 mm	±0.9 mm	±0.3 mm
Field of View	45.2 mm	20.8 mm	11 mm	5.5 mm

MAINFRAME

Envelope Dimensions (LWH)
Electrical Requirements
Weight

438mm x 518mm x 662mm
120 VAC, 60 Hz
70lbs (Mainframe)



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